

**Notice of References Cited**

Application/Control No.

10/574,282

Applicant(s)/Patent Under  
Reexamination  
SHIKAI ET AL.

Examiner

Eduardo Colon-Santana

Art Unit

2837

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0155185 A1	08-2003	Nomura et al.	187/266
*	B	US-2006/0102434 A1	05-2006	Nomura et al.	187/266
*	C	US-7,228,943 B2	06-2007	Kugiya et al.	187/393
*	D	US-7,428,951 B2	09-2008	Ito, Kazumasa	188/69
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004231355 A	08-2004	Japan	FUNAI, KIYOSHI	B66B 01/32
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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